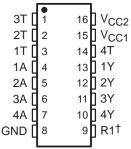
QUADRUPLE LINE RECEIVER

SLLS083B - NOVEMBER 1970 - REVISED MAY 1995

- Meets or Exceeds the Requirements of ANSI Standard EIA/TIA-232-E and ITU **Recommendation V.28**
- Input Resistance . . . 3 $k\Omega$ to 7 $k\Omega$ Over Full EIA/TIA-232-E Voltage Range
- Input Threshold Adjustable to Meet Fail-Safe Requirements Without Using **External Components**
- **Built-In Hysteresis for Increased Noise Immunity**
- **Inverting Output Compatible With TTL**
- **Output With Active Pullup for Symmetrical Switching Speeds**
- Standard Supply Voltages . . . 5 V or 12 V

D OR N PACKAGE (TOP VIEW)



† For function of R1, see schematic

description

The SN75154 is a monolithic low-power Schottky line receiver designed to satisfy the requirements of the standard interface between data terminal equipment and data communication equipment as defined by ANSI Standard EIA/TIA-232-E. Other applications are for relatively short, single-line, point-to-point data transmission and for level translators. Operation is normally from a single 5-V supply; however, a built-in option allows operation from a 12-V supply without the use of additional components. The output is compatible with most TTL circuits when either supply voltage is used.

In normal operation, the threshold-control terminals are connected to the V_{CC1} terminal, even if power is being supplied via the alternate V_{CC2} terminal. This provides a wide hysteresis loop, which is the difference between the positive-going and negative-going threshold voltages. See typical characteristics. In this mode of operation, if the input voltage goes to zero, the output voltage will remain at the low or high level as determined by the previous input.

For fail-safe operation, the threshold-control terminals are open. This reduces the hysteresis loop by causing the negative-going threshold voltage to be above zero. The positive-going threshold voltage remains above zero as it is unaffected by the disposition of the threshold terminals. In the fail-safe mode, if the input voltage goes to zero or an open-circuit condition, the output will go to the high level regardless of the previous input condition.

The SN75154 is characterized for operation from 0°C to 70°C.



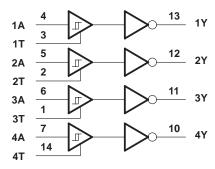
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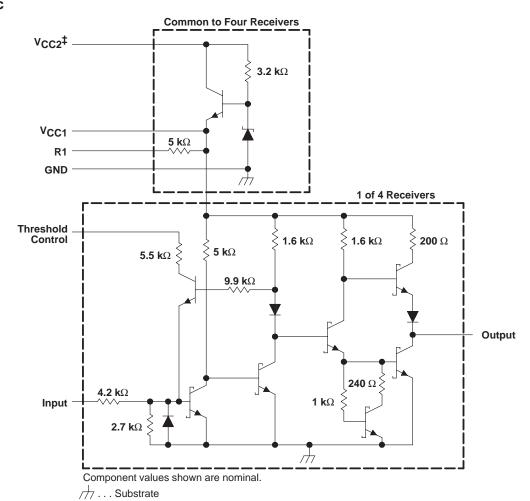
logic symbol†

口区 1A 13 1Y 3 1T THRS ADJ 5 2A 12 2Y 2 2T 6 3A 11 1 3Y **3T** 7 4A 10 4Y 14 4T

logic diagram (positive logic)



schematic



 $^{^{\}ddagger}$ When V_{CC1} is used, V_{CC2} may be left open or shorted to V_{CC1}. When V_{CC2} is used, V_{CC1} must be left open or connected to the threshold control pins.



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Normal supply voltage, V _{CC1} (see Note 1)	7 V
Alternate supply voltage, V _{CC2}	
Input voltage, V _I	
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW
N	1150 mW	9.2 mW/°C	736 mW
NS	625 mW	5.0 mW/°C	400 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Normal supply voltage, V _{CC1}	4.5	5	5.5	V
Alternate supply voltage, V _{CC2}	10.8	12	13.2	V
High-level input voltage, V _{IH} (see Note 2)	3		15	V
Low-level input voltage, V _{IL} (see Note 2)	-15		-3	V
High-level output current, IOH			-400	μΑ
Low-level output current, IOL			16	mA
Operating free-air temperature, TA	0		70	°C

NOTE 2: The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for logic and threshold levels only, e.g., when 0 V is the maximum, the minimum limit is a more negative voltage.



NOTE 1: Voltage values are with respect to network GND terminal.

SN75154 QUADRUPLE LINE RECEIVER

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
V	Positive-going input	Normal operation	1		0.8	2.2	3	V	
V _{IT+}	threshold voltage	Fail-safe operation	'		0.8	2.2	3	V	
\/	Negative-going input	Normal operation	1		-3	-1.1	0	V	
V _{IT} _	threshold voltage	Fail-safe operation] '		0.8	1.4	3	V	
\/.	Hysteresis voltage	Normal operation	1		0.8	3.3	6	V	
V _{hys}	$(V_{\text{IT+}} - V_{\text{IT-}})$	Fail-safe operation] '		0	0.8	2.2	V	
VOH High-level output voltage		1	I _{OH} = -400 μA	2.4	3.5		V		
VOL	Low-level output voltage		1	I _{OL} = 16 mA		0.29	0.4	V	
				$\Delta V_{I} = -25 \text{ V to } -14 \text{ V}$	3	5	7		
				$\Delta V_{I} = -14 \text{ V to } -3 \text{ V}$	3	5	7		
rį	Input resistance		2	$\Delta V_I = -3 \text{ V to 3 V}$	3	6	8	kΩ	
				$\Delta V_I = 3 V \text{ to } 14 V$	3	5	7	Naz	
				$\Delta V_I = 14 \text{ V to } 25 \text{ V}$	3	5	7	1	
V _{I(open)} Open-circuit input voltage		3	I _I = 0	0	0.2	2	V		
IOS Short-circuit output current [‡]		4	$V_{CC1} = 5.5 \text{ V}, \qquad V_{I} = -5 \text{ V}$	-10	-20	-40	mA		
ICC1 Supply current from V _{CC1} ICC2 Supply current from V _{CC2}		- 5	$V_{CC1} = 5.5 \text{ V}, \qquad T_A = 25^{\circ}\text{C}$		20	35	m 1		
			$V_{CC2} = 13.2 \text{ V}, T_A = 25^{\circ}\text{C}$		23	40	mA		

switching characteristics, $V_{CC1} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$, N = 10

PARAMETER F		TEST FIGURE	TEST CONDITIONS		MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output					11		ns
tPHL	Propagation delay time, high- to low-level output	6	C. 50 7 F	F, $R_L = 390 \Omega$		8		ns
tTLH	Transition time, low- to high-level output	б	$C_L = 50 pF$,			7		ns
tTHL	Transition time, high- to low-level output					2.2		ns

[†] All typical values are at V_{CC1} = 5 V, T_A = 25°C. ‡ Not more than one output should be shorted at a time.

TYPICAL CHARACTERISTICS

OUTPUT VOLTAGE ٧S **INPUT VOLTAGE** V_{CC1} = 5 V V_O - Output Voltage - V T_A = 25°C Normal ____ Operation Fail-Safe Operation V_{IT}-VIT+ See Note A 0 -25 -4 -3 -2 -1 0 1 2 3 25 V_I - Input Voltage - V

NOTE A: For normal operation, the threshold controls are connected to V_{CC1} . For fail-safe operation, the threshold controls are open.

Figure 1

PARAMETER MEASUREMENT INFORMATION

dc test circuits†

TEST TABLE

TEST	MEASURE	Α	Т	Y	V _{CC1}	V _{CC2}
Open-circuit input (fail safe)	Voн	Open	Open	loh	4.5 V	Open
Open-circuit input (fail safe)	Voн	Open	Open	loh	Open	10.8 V
V.— min V.— min (fail safa)	Voн	0.8 V	Open	loh	5.5 V	Open
V _{IT+} min, V _{IT} min (fail safe)	Voн	0.8 V	Open	loh	Open	13.2 V
Viz. min (normal)	Voн	Note A	V _{CC1}	loh	5.5 V and T	Open
V _{IT+} min (normal)	Voн	Note A	V _{CC1}	loh	Т	13.2 V
V V	Voн	-3 V	V _{CC1}	loh	5.5 V and T	Open
V _{IL} max, V _{IT+} min (normal)	Voн	-3 V	V _{CC1}	loh	Т	13.2 V
Vull min Vita may Vita may (fail cafe)	V _{OL}	3 V	Open	l _{OL}	4.5 V	Open
V _{IH} min, V _{IT+} max, V _{IT-} max (fail safe)	V _{OL}	3 V	Open	l _{OL}	Open	10.8 V
V min V. — may (normal)	V _{OL}	3 V	V _{CC1}	l _{OL}	4.5 V and T	Open
V _{IH} min, V _{IT+} max (normal)	VOL	3 V	V _{CC1}	loL	Т	10.8 V
V— may (narmal)	VOL	Note B	V _{CC1}	loL	5.5 V and T	Open
V _{IT} max (normal)	VOL	Note B	V _{CC1}	loL	Т	13.2 V

NOTES: A. Momentarily apply –5 V, then 0.8 V. B. Momentarily apply 5 V, then GND.

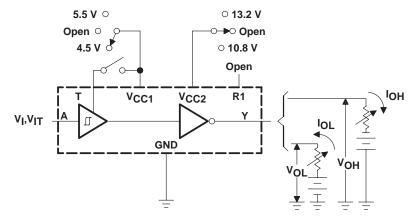
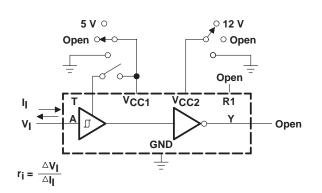


Figure 2. V_{IH} , V_{IL} , V_{IT+} , V_{IT-} , V_{OH} , V_{OL}

[†] Arrows indicate actual direction of current flow. Current into a terminal is a positive value.

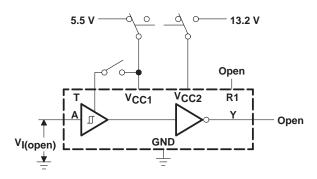
PARAMETER MEASUREMENT INFORMATION

dc test circuits† (continued)



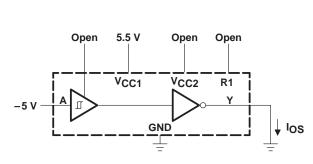
IEST IABLE						
Т	V _{CC1}	V _{CC2}				
Open	5 V	Open				
Open	GND	Open				
Open	Open	Open				
VCC1	T and 5 V	Open				
GND	GND	Open				
Open	Open	12 V				
Open	Open	GND				
VCC1	Т	12 V				
VCC1	Т	GND				
VCC1	Т	Open				

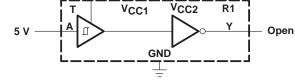
Figure 3. Input Resistance



TEST TABLE T VCC1 VCC2 Open 5.5 V Open VCC1 5.5 V Open Open Open 13.2 V VCC1 T 13.2 V

Figure 4. Input Voltage (Open)





Each output is tested separately.

All four line receivers are tested simultaneously.

5.5 V

ICC1

Open

Figure 5. Output Short-Circuit Current

Figure 6. Supply Current

⁻ 13.2 V

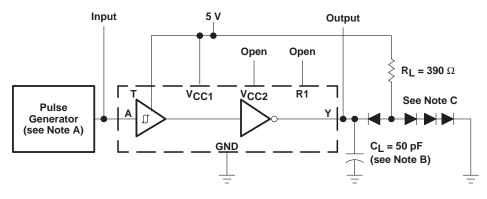
Open

I_{CC2}

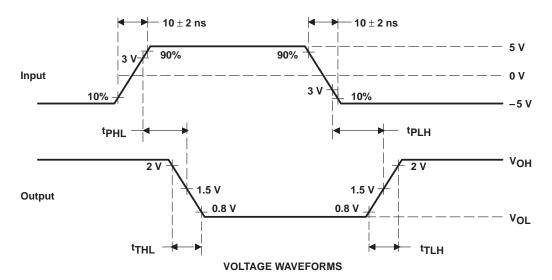


[†] Arrows indicate actual direction of current flow. Current into a terminal is a positive value.

PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



NOTES: A. The pulse generator has the following characteristics: Z_0 = 50 Ω , $t_W \le$ 200 ns, duty cycle \le 20%.

- B. C_L includes probe and jig capacitance.
- C. All diodes are 1N3064.

Figure 6. Test Circuit and Voltage Waveforms

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